

Abstract of the Disclosure

A test device for testing integrated circuits includes a lid and a base joined at a hinge and secured together with a latch. Within the base is some form of socket body that electrically connects the integrated circuit under test to the item the socket is mounted to (i.e. load board). Attached to the lid are cam ratcheting levers. A pressure plate is attached to cam ratcheting levers. The cam ratcheting levers provide a rotating means for lowering a pressure plate by the use of the cam groove within the cam ratcheting levers. The means for lowering a pressure plate may allow incremental lowering of a pressure plate through the ratcheting action of the cam ratcheting levers. The base may include a sight groove for examination of the integrated circuit and internal socket parts.